

N-CHANNEL POWER MOSFET

SML20J175

- Fast Switching and Low leakage
- 100% Avalanche Tested
- Popular SOT-227 Package

StarMOS is a new generation of high voltage N-Channel enhancement mode power MOSFET's. This new technology minimises the JFET effect, increases packing density and reduces the on-resistance. StarMOS also achieve faster switching speeds through optimised gate layout.



ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise stated)

V _{DS}	Drain – Source Voltage	200V
V _{GS}	Gate – Source Voltage Continuous	
M	Gate – Source Voltage Transient	±30V
I _D	Continuous Drain Current	175A
I _{DM}	Pulsed Drain Current ⁽¹⁾	700A
R _{DS(on)}	On-State Drain-Source Resistance	0.011Ω
P _D	Total Power Dissipation	700W
	Derate Above 25°C	5.6W/°C
E _{AR}	Repetitive Avalanche Energy ⁽¹⁾	30mJ
E _{AS}	Single Pulse Avalanche Energy ⁽⁴⁾	3600mJ
I _{AR}	Avalanche Current (Repetitive and Non-Repetitive) ⁽¹⁾	175A
T _J	Junction Temperature Range	-55 to +150°C
T _{stg}	Storage Temperature Range	-55 to +150°C
T _L	Lead Temperature: 0.063" from Case for 10 sec	300°C

THERMAL / PACKAGE CHARACTERISTICS

Symbols	Parameters	Min.	Typ.	Max.	Units
R _{θJC}	Thermal Resistance, Junction To Case			0.18	°C/W
θ _{JA}	Thermal Resistance, Junction To Ambient			0.40	°C/W
V _{isolation}	RMS Voltage (50-60Hz Sinusoidal waveform from terminals to mounting base for 1min)	2500			V
Torque	Device Mounting Screws and Electrical Terminations			1.4	Nm

Notes

- (1) Repetitive Rating: Pulse width limited by maximum junction temperature
- (2) Pulse Width ≤ 380us, δ ≤ 2%
- (3) See MIL-STD-750 Method 3471
- (4) Peak I_L = 175A, L = 235μH, R_G = 25Ω, Starting T_J = 25°C

Semelab Limited reserves the right to change test conditions, parameter limits and package dimensions without notice. Information furnished by Semelab is believed to be both accurate and reliable at the time of going to press. However Semelab assumes no responsibility for any errors or omissions discovered in its use. Semelab encourages customers to verify that datasheets are current before placing orders.



A subsidiary of
TT electronics plc.

		Test Conditions	Min.	Typ	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0$ $I_D = 250\mu A$	200			V
$I_{D(on)}^{(2)}$	On-State Drain Current	$(V_{DS} > I_{D(on)} \times R_{DS(on)})_{MAX}$ $V_{GS} = 10V$	175			A
$R_{DS(on)}^{(2)}$	Drain-Source On-State Resistance	$V_{GS} = 10V$ $0.5 I_{D(cont)}$			0.011	Ω
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ $I_D = 5mA$	2		4	V
I_{GSS}	Gate-Source Leakage Current	$V_{GS} = \pm 20V$			± 100	nA
I_{DSS}	Zero Gate Voltage Drain Current	$V_{GS} = 0$ $V_{DS} = V_{DSS}$			100	μA
		$V_{DS} = 0.8V_{DSS}$ $T_J = 125^\circ C$			500	

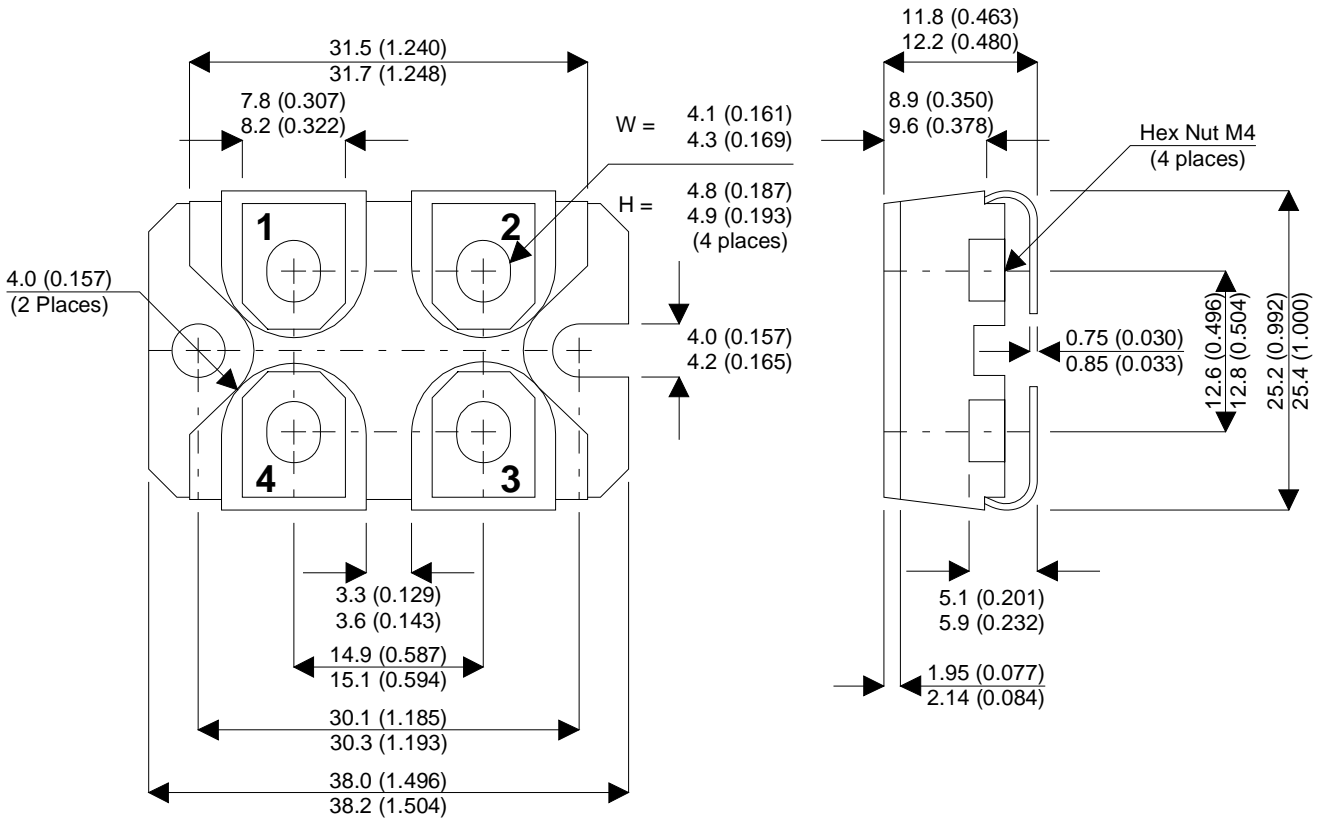
DYNAMIC CHARACTERISTICS

						pF
				1350		
$Q_g^{(3)}$	Total Gate Charge	$V_{GS} = 10V$		690		
Q_{gs}	Gate-Source Charge	$I_D = 0.5 I_{D(cont)}$		95		nC
Q_{gd}	Gate-Drain Charge		$V_{DS} = 0.5 V_{DSS}$		290	
$t_{d(on)}$	Turn-On Delay Time	$V_{GS} = 15V$ $V_{DD} = 0.5 V_{DSS}$		20		ns
t_r	Rise Time			40		
$t_{d(off)}$	Turn-Off Delay Time		$I_D = 0.5 I_{D(cont)}$ $R_G = 0.6\Omega$		75	
t_f	Fall Time			10		

SOURCE-DRAIN DIODE CHARACTERISTICS

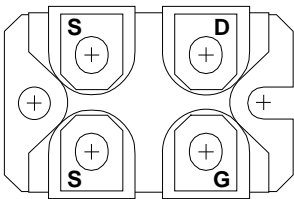
⁽¹⁾	Pulsed Source Current				700	A
$V_{SD}^{(2)}$	Diode Forward Voltage	$I_S = - I_{D(cont)}$ $V_{GS} = 0$			1.3	V
t_{rr}	Reverse Recovery Time	$I_S = - I_{D(cont)}$			460	ns
Q_{rr}	Reverse Recovery Charge	$dI_S/dt = 100A/\mu s$			7	μC

Dimensions in mm (inches)



227 (ISOTOP)

Pins 1 & 4 - Source Pin 2 - Drain Pin 3 - Gate



* Source terminals are shorted internally. Current handling capability is equal for either Source terminal.